•	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/057,672	CLANCY ET AL.
Examiner	Art Unit
Dienane M. Bayard	2141

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Class	Subclass	Date	Examiner
709	250	4/28/2005	D,В
709	222	4/28/2005	DB
713	193	4/28/2005	DB
370	330	4/28/2005	DB
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